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Substitute for form 1449A/PTO (modified) <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (use as many sheets as necessary)				<b>Complete if known</b>	
Sheet				Application Number	Not yet assigned
				Filing Date	Concurrently Herewith
				First Named Inventor	Horst Haussecker
				Group Art Unit	Not yet assigned
				Examiner Name	Not yet assigned
				Attorney Docket	42P14242X
Sheet	1	of	3		

**U.S. PATENT DOCUMENTS**

Examiner Initials	Cite No. <sup>1</sup>	U.S. Patent Document Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Passages or Figures Appear
BL	5,472,881			Beebe, et al.	12/05/1995	
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V	6,360,020			Panis	03/19/2002	

**OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS**

Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
BL		United States Patent Application Publication, Publication No. US 2001/0052257, Magerle, Publication Date December 20, 2001.	

Examiner Signature	<i>Beebe</i>	Date Considered	08/29/05
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<sup>1</sup>Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard St.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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BL		ANDO, et al., "A High-Speed Atomic Force Microscope for Studying Biological Macromolecules," <i>PNAS</i> , Vol. 98, No. 22, pp. 12468-12472, October 2001.	
		CLAUSS, et al., "Atomic Resolution STM Imaging of a Twisted Single-Wall Carbon Nanotube," <i>Physical Review B</i> , Volume 58, Number 8, pp. 4266-4269, August 1998.	
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		FREITAG, et al., "Local Electronic Properties of Single-Wall Nanotube Circuits Measured by Conducting-Tip AFM," <i>Physical Review B</i> , Volume 62, Number 4, pp. 2307-2310, July 2000.	
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		HIRAHARA, et al., "One-Dimensional Metallofullerene Crystal Generated Inside Single-Walled Carbon Nanotubes," <i>Physical Review Letters</i> , Volume 85, Number 25, pp. 5384-5387, December 2000.	
		HUANG, et al., "Directed Assembly of One-Dimensional Nanostructures into Functional Networks," <i>Science</i> , Vol. 291, pp. 630-633, January 2001.	
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Examiner Signature	<i>Bruce</i>	Date Considered	06/29/05
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BL		KOBAYASHI, et al., "Imaging of Fullerene Molecules on Si(111)-7 7 Surface with NC-AFM," <i>Applied Surface Science</i> , 157, pp. 228-232, 2000.			
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BL		UCHIHASHI, et al, "Application of Noncontact-Mode Atomic Force Microscopy to Molecular Imaging," Retrieved from the Internet on July 3, 2002, URL://<http://www.foresight.org/Conferences/MNT7/Abstracts/Uchihashi/> 2 pages.			

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